

December 2010

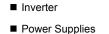
FDD4685_F085

P-Channel PowerTrench[®] MOSFET

-40V, -32A, 35mΩ

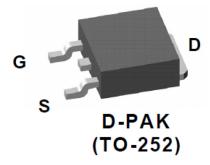
Features

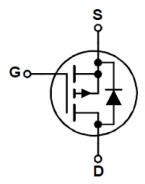
- Typ $r_{DS(on)}$ = 23m Ω at V_{GS} = -10V, I_D = -8.4A
- Typ $r_{DS(on)}$ = 30m Ω at V_{GS} = -4.5V, I_D = -7A
- Typ $Q_{g(TOT)}$ = 19nC at V_{GS} = -5V
- \blacksquare High performance trench technology for extremely low $r_{DS(\alpha n)}$
- RoHS Compliant
- Qualified to AEC Q101



Applications







MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain to Source Voltage	-40	V	
V_{GS}	Gate to Source Voltage	±20	V	
	Drain Current Continuous (T _C <90°C, V _{GS} = 10V)	-32	Α	
I _D	Pulsed		See Figure 4	A
E _{AS}	Single Pulse Avalanche Energe	(Note 1)	121	mJ
D	Power Dissipation		83	W
P_D	Dreate above 25°C		0.56	W/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to +175	°C

Thermal Characteristics

$R_{\theta JC}$	Maximum Thermal Resistance Junction to Case	1.8	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD4685	FDD4685_F085	TO252	13"	12mm	2500 units

Test Conditions

Min

Тур

Max

Units

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

Off Cha	Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-40	-	-	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	ID = -250μA, referenced to 25°C	-	-33	-	mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -32V$,	-	-	-1	μΑ	
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA	

On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-1.6	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	ID = -250μA, referenced to 25°C	-	4.9	-	mV/°C
		$I_D = -8.4A, V_{GS} = -10V$	-	23	27	
r _{no} ,	Drain to Source On Resistance	$I_D = -7A, V_{GS} = -4.5V$	-	30	35	mΩ
r _{DS(on)} Drain to Source On Resistance	$I_D = -8.4A, V_{GS} = -10V,$ $T_J = 150^{\circ}C$	-	38	45	11122	
g _{FS}	Forward Transconductance	$I_D = -8.4A, V_{DS} = -5V,$	1	23	1	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V = 20V V = 0V	-	1790	2380	pF
Coss	Output Capacitance	$V_{DS} = -20V, V_{GS} = 0V,$ f = 1MHz	-	260	345	pF
C _{rss}	Reverse Transfer Capacitance	1 - 111112	-	140	205	pF
R_G	Gate Resistance	f = 1MHz	-	4	-	Ω
$Q_{g(TOT)}$	Total Gate Charge		-	19	27	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DD} = -20V, V_{GS} = -5V$	-	5.6	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	I _D = -8.4A	-	6.1	-	nC

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Outliebing Observatoristics						

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	8	16	ns
t _r	Rise Time	V _{DD} = -20V, I _D = -8.4A	-	15	27	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = -10V, R_{GEN} = 6Ω	-	34	55	ns
t _f	Fall Time		1	14	26	ns

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	I_{SD} = -8.4A, V_{GS} =0V	-	-0.85	-1.2	V
t _{rr}	Reverse Recovery Time	I = 9.4A dI /dt = 100A/vo	-	30	45	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = -8.4A$, $dI_{SD}/dt = 100A/\mu s$	-	31	47	nC

Notes

1: Starting T_J = 25°C, L = 3mH, I_{AS} = 9A, V_{GS} = 10V, V_{DD} = 40V during the inductor charging time and 0V during the time in avalanche.

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/
All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

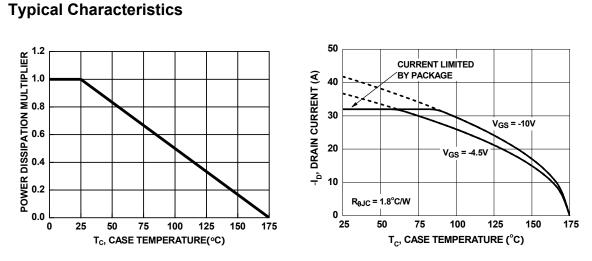


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature



t, RECTANGULAR PULSE DURATION(s)
Figure 3. Normalized Maximum Transient Thermal Impedance

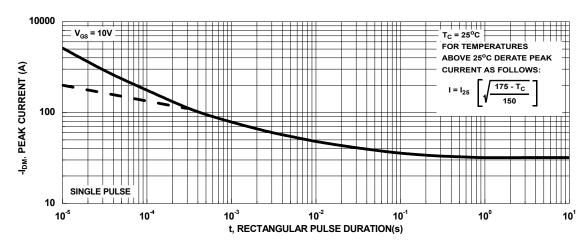


Figure 4. Peak Current Capability

Typical Characteristics

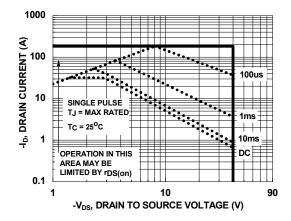
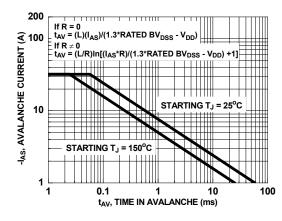


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability

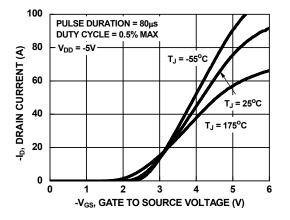


Figure 7. Transfer Characteristics

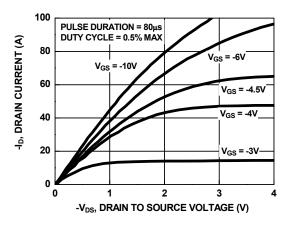


Figure 8. Saturation Characteristics

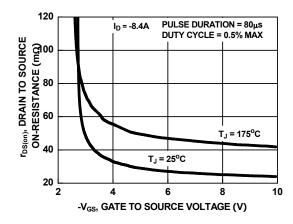


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

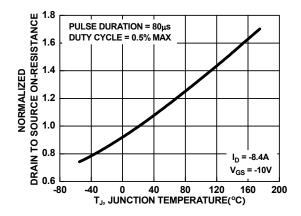


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics

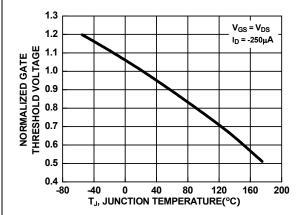


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

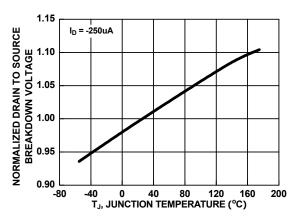


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

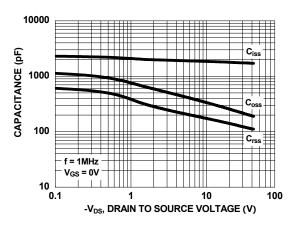


Figure 13. Capacitance vs Drain to Source Voltage

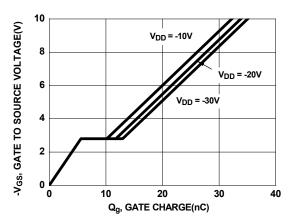


Figure 14. Gate Charge vs Gate to Source Voltage





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